Power MOSFET

30 V, 53 A, Single N-Channel, SO-8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Para	Symbol	Value	Unit		
Drain-to-Source Voltage			V _{DSS}	30	V
<u> </u>					-
Gate-to-Source Vo	tage		V_{GS}	20	V
Continuous Drain Current R _{0.1A}		T _A = 25°C	I _D	11	Α
(Note 1)		T _A = 85°C		8.0	
Power Dissipation R _{0JA} (Note 1)		T _A = 25°C	P _D	2.2	W
Continuous Drain Current R _{BJA}		T _A = 25°C	ID	7.0	Α
(Note 2)	Steady	T _A = 85°C		5.0	
Power Dissipation R _{θJA} (Note 2)	State	T _A = 25°C	P _D	0.88	W
Continuous Drain		T _C = 25°C	I _D	53	Α
Current R _{θJC} (Note 1)		T _C = 85°C		38	
Power Dissipation R _{0JC} (Note 1)		T _C = 25°C	P _D	47.2	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	106	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Boo	I _S	46	Α		
Drain to Source dV/	dV/dt	6.0	V/ns		
Single Pulse Drain-to–Source Avalanche Energy (V_{DD} = 50 V, V_{GS} = 10 V, I_L = 24 A_{pk} , L = 1.0 mH, R_G = 25 Ω)			EAS	286	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

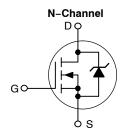
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

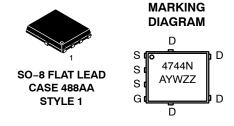


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
30 V	10 mΩ @ 10 V	53 A	
00 V	14 mΩ @ 4.5 V		





4744N = Specific Device Code A = Assembly Location

Y = Year W = Work Week ZZ = Lot Traceability

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4744NT1G	SO-8 FL (Pb-Free)	1500 Tape & Reel
NTMFS4744NT3G	SO-8 FL (Pb-Free)	5000 Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.65	
Junction-to-Ambient - Steady State (Note 1)	$R_{ hetaJA}$	56.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	142.4	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				10		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	T _J = 25 °C			1.0	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = 20 V				100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V to	I _D = 30 A		7.6		
		11.5 V	I _D = 15 A		7.3		mΩ
			I _D = 10 A		7.3	10	
		V _{GS} = 4.5 V	I _D = 30 A		10.4		
			I _D = 15 A		10.1		
			I _D = 10 A		9.9	14	1
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			25		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE						
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			1300		pF
Output Capacitance	C _{OSS}				550		
Reverse Transfer Capacitance	C _{RSS}				132		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			10	17	nC
Threshold Gate Charge	Q _{G(TH)}				0.9		
Gate-to-Source Charge	Q_{GS}				1.8		
Gate-to-Drain Charge	Q_{GD}				5.9		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			25	37	nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 30 A, R_{G} = 3.0 Ω			12		
Rise Time	t _r				203		ns
Turn-Off Delay Time	t _{d(OFF)}				14		
Fall Time	t _f				83		

^{3.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.

Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

^{4.} Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)				•		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 30 A, R_{G} = 3.0 Ω			7.0		- ns
Rise Time	t _r				94		
Turn-Off Delay Time	t _{d(OFF)}				23		
Fall Time	t _f				4.7		
DRAIN-SOURCE DIODE CHARACTI	ERISTICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V, I _S = 30 A	T _J = 25°C		0.78	1.2	V
			T _J = 125°C		0.7		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			37	60	ns
Charge Time	t _a				21		
Discharge Time	t _b				17		
Reverse Recovery Charge	Q _{RR}				37		nC
PACKAGE PARASITIC VALUES					•		
Source Inductance	L _S	T _A = 25°C			0.65		nΗ
Drain Inductance	L _D				0.005		
Gate Inductance	L _G				1.84		
Gate Resistance	R_{G}				2.0	5.0	Ω

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

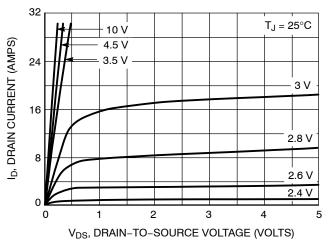


Figure 1. On-Region Characteristics

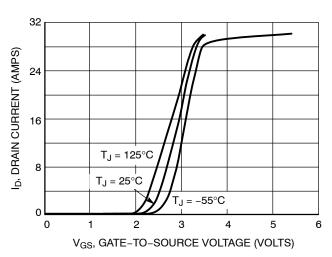


Figure 2. Transfer Characteristics

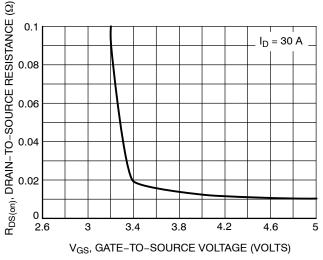


Figure 3. On-Resistance vs. Gate-to-Source Voltage

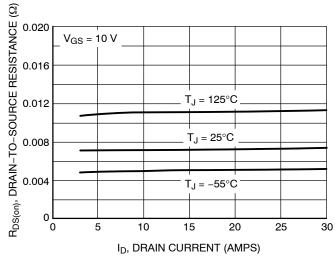


Figure 4. On-Resistance vs. Drain Current and Temperature

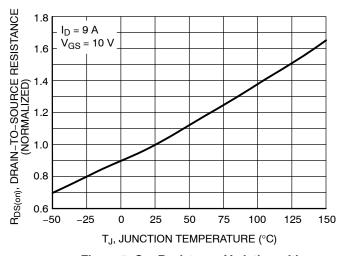


Figure 5. On–Resistance Variation with Temperature

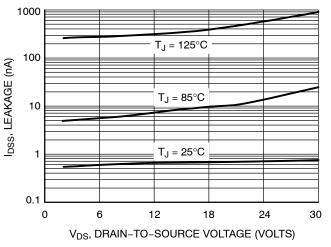
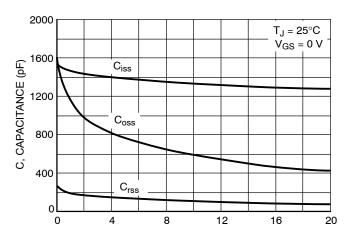


Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

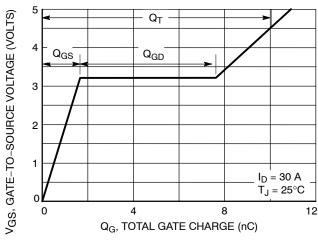


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



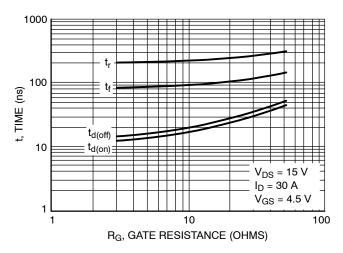


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

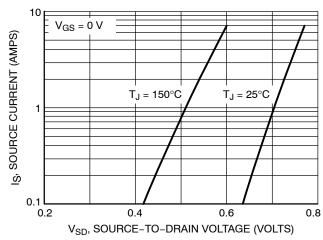


Figure 10. Diode Forward Voltage vs. Current

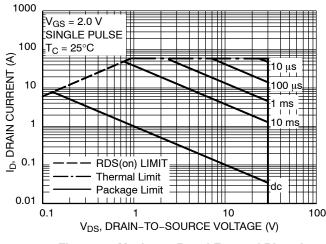


Figure 11. Maximum Rated Forward Biased Safe Operating Area

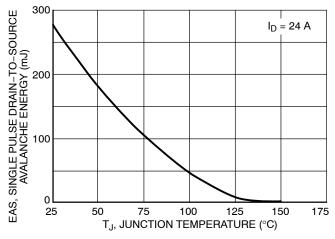


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

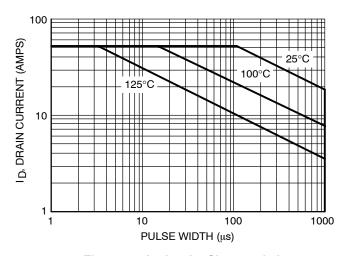
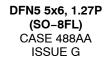
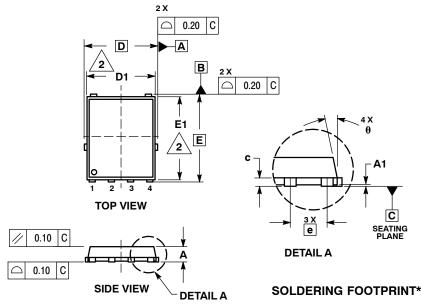


Figure 13. Avalanche Characteristics

PACKAGE DIMENSIONS





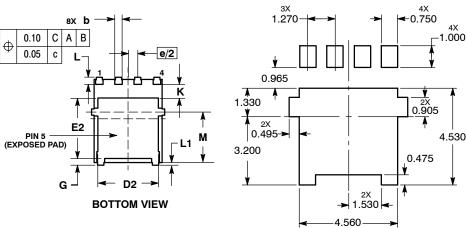
NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETER. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	1.00	1.10			
A1	0.00		0.05			
b	0.33	0.41	0.51			
С	0.23	0.28	0.33			
D		5.15 BSC	;			
D1	4.50	4.90	5.10			
D2	3.50		4.22			
E		6.15 BSC				
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е		1.27 BSC				
G	0.51	0.61	0.71			
K	1.20	1.35	1.50			
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
М	3.00	3.40	3.80			
θ	0 °		12 °			

- STYLE 1: PIN 1. SOURCE 2. SOURCE

 - 3. SOURCE GATE
 - 5. DRAIN



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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